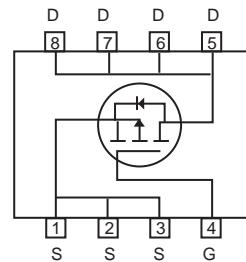
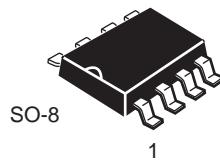


P-Channel Enhancement Mode Field Effect Transistor

FEATURES

- -30V, -9.3A, $R_{DS(ON)} = 18m\Omega$ @ $V_{GS} = -10V$.
 $R_{DS(ON)} = 30m\Omega$ @ $V_{GS} = -4.5V$.
- Super high dense cell design for extremely low $R_{DS(ON)}$.
- High power and current handing capability.
- Lead free product is acquired.
- Surface mount Package.



ABSOLUTE MAXIMUM RATINGS $T_A = 25^\circ C$ unless otherwise noted

Parameter	Symbol	Limit	Units
Drain-Source Voltage	V_{DS}	-30	V
Gate-Source Voltage	V_{GS}	± 20	V
Drain Current-Continuous	I_D	-9.3	A
Drain Current-Pulsed ^a	I_{DM}	-37	A
Maximum Power Dissipation	P_D	2.5	W
Operating and Store Temperature Range	T_J, T_{stg}	-55 to 150	$^\circ C$

Thermal Characteristics

Parameter	Symbol	Limit	Units
Thermal Resistance, Junction-to-Ambient ^b	$R_{\theta JA}$	50	$^\circ C/W$

**Electrical Characteristics** $T_A = 25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Test Condition	Min	Typ	Max	Units
Off Characteristics						
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{\text{GS}} = 0\text{V}, I_D = -250\mu\text{A}$	-30			V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{\text{DS}} = -24\text{V}, V_{\text{GS}} = 0\text{V}$			-1	μA
Gate Body Leakage Current, Forward	I_{GSSF}	$V_{\text{GS}} = 20\text{V}, V_{\text{DS}} = 0\text{V}$			100	nA
Gate Body Leakage Current, Reverse	I_{GSSR}	$V_{\text{GS}} = -20\text{V}, V_{\text{DS}} = 0\text{V}$			-100	nA
On Characteristics^c						
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{GS}} = V_{\text{DS}}, I_D = -250\mu\text{A}$	-1		-3	V
Static Drain-Source On-Resistance	$R_{\text{DS}(\text{on})}$	$V_{\text{GS}} = -10\text{V}, I_D = -7\text{A}$		14	18	$\text{m}\Omega$
		$V_{\text{GS}} = -4.5\text{V}, I_D = -5.8\text{A}$		23	30	$\text{m}\Omega$
Dynamic Characteristics^d						
Forward Transconductance	g_{FS}	$V_{\text{DS}} = -10\text{V}, I_D = -7\text{A}$		15		S
Input Capacitance	C_{iss}	$V_{\text{DS}} = -15\text{V}, V_{\text{GS}} = 0\text{V}, f = 1.0 \text{ MHz}$		2020		pF
Output Capacitance	C_{oss}			395		pF
Reverse Transfer Capacitance	C_{rss}			202		pF
Switching Characteristics^d						
Turn-On Delay Time	$t_{\text{d}(\text{on})}$	$V_{\text{DD}} = -10\text{V}, I_D = -1\text{A}, V_{\text{GS}} = -10\text{V}, R_{\text{GEN}} = 6\Omega$		16	30	ns
Turn-On Rise Time	t_r			7	15	ns
Turn-Off Delay Time	$t_{\text{d}(\text{off})}$			105	200	ns
Turn-Off Fall Time	t_f			40	80	ns
Total Gate Charge	Q_g	$V_{\text{DS}} = -15\text{V}, I_D = -7\text{A}, V_{\text{GS}} = -4.5\text{V}$		16.4	22	nC
Gate-Source Charge	Q_{gs}			5.8		nC
Gate-Drain Charge	Q_{gd}			6.5		nC
Drain-Source Diode Characteristics and Maximum Ratings						
Drain-Source Diode Forward Current ^b	I_S				-2.1	A
Drain-Source Diode Forward Voltage ^c	V_{SD}	$V_{\text{GS}} = 0\text{V}, I_S = -2.1\text{A}$			-1.2	V

Notes :

a.Repetitive Rating : Pulse width limited by maximum junction temperature.

b.Surface Mounted on FR4 Board, $t \leq 10 \text{ sec}$.c.Pulse Test : Pulse Width $\leq 300\mu\text{s}$, Duty Cycle $\leq 2\%$.

d.Guaranteed by design, not subject to production testing.

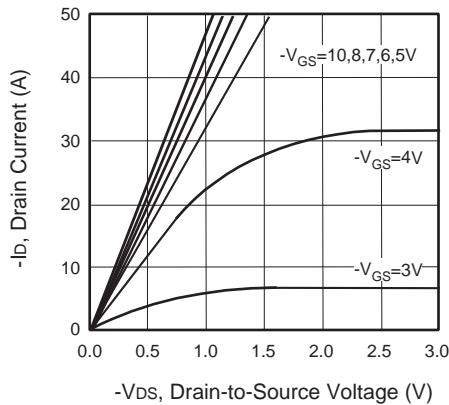


Figure 1. Output Characteristics

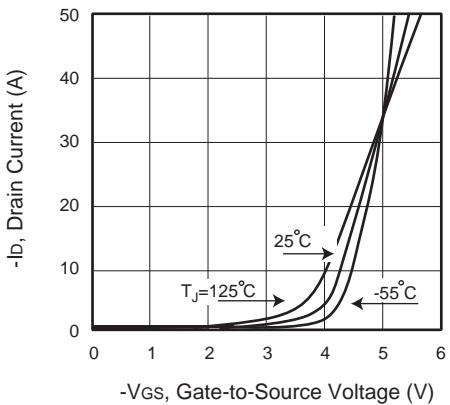


Figure 2. Transfer Characteristics

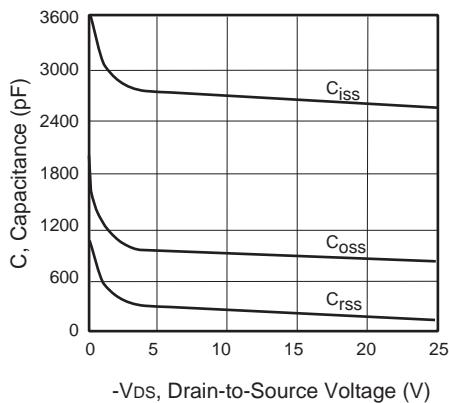


Figure 3. Capacitance

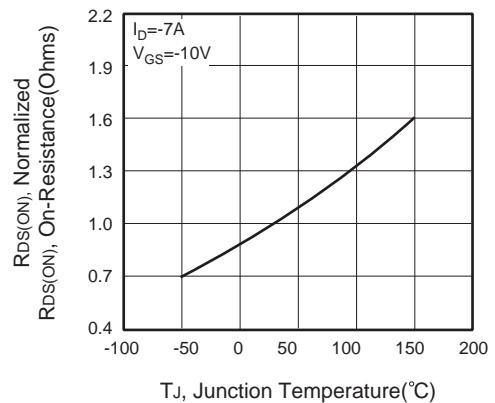


Figure 4. On-Resistance Variation with Temperature

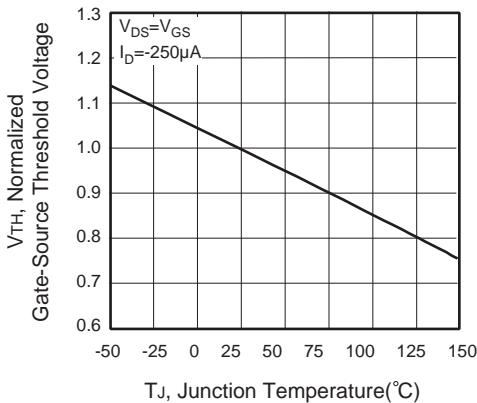


Figure 5. Gate Threshold Variation with Temperature

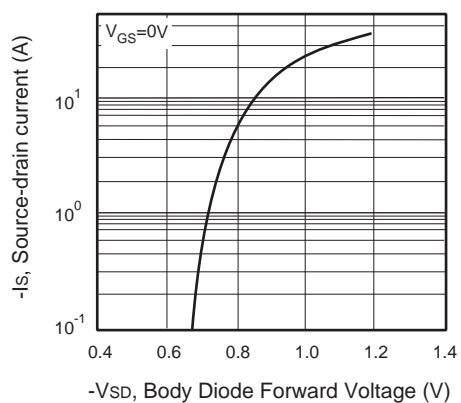


Figure 6. Body Diode Forward Voltage Variation with Source Current

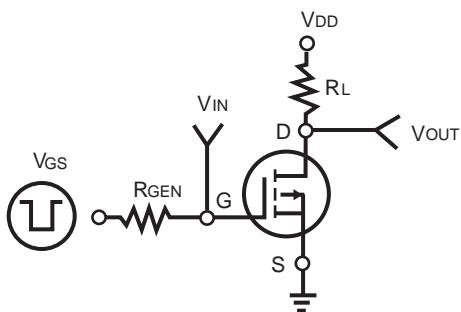
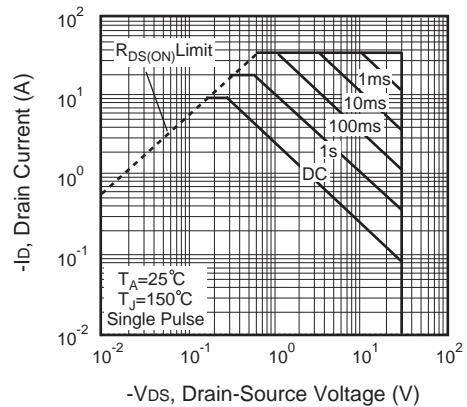
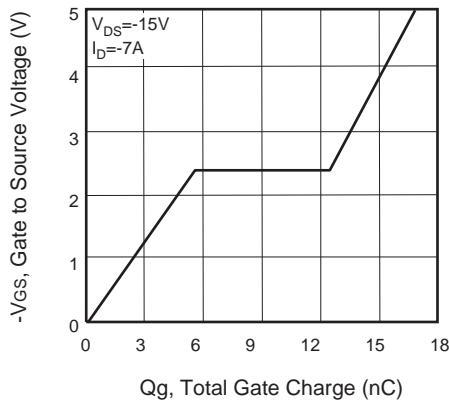


Figure 9. Switching Test Circuit

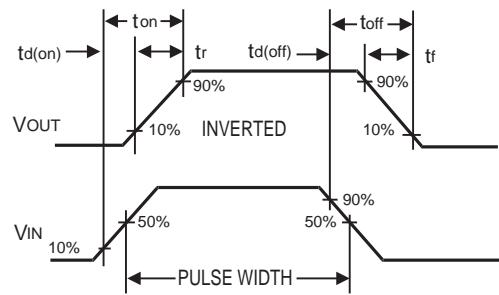


Figure 10. Switching Waveforms

